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HEIGHT CALIBRATION OF SCANNING PROBE MICROSCOPE ACTUATORS
Osamah M. El Rifai et al.
Application No. 10/722,806

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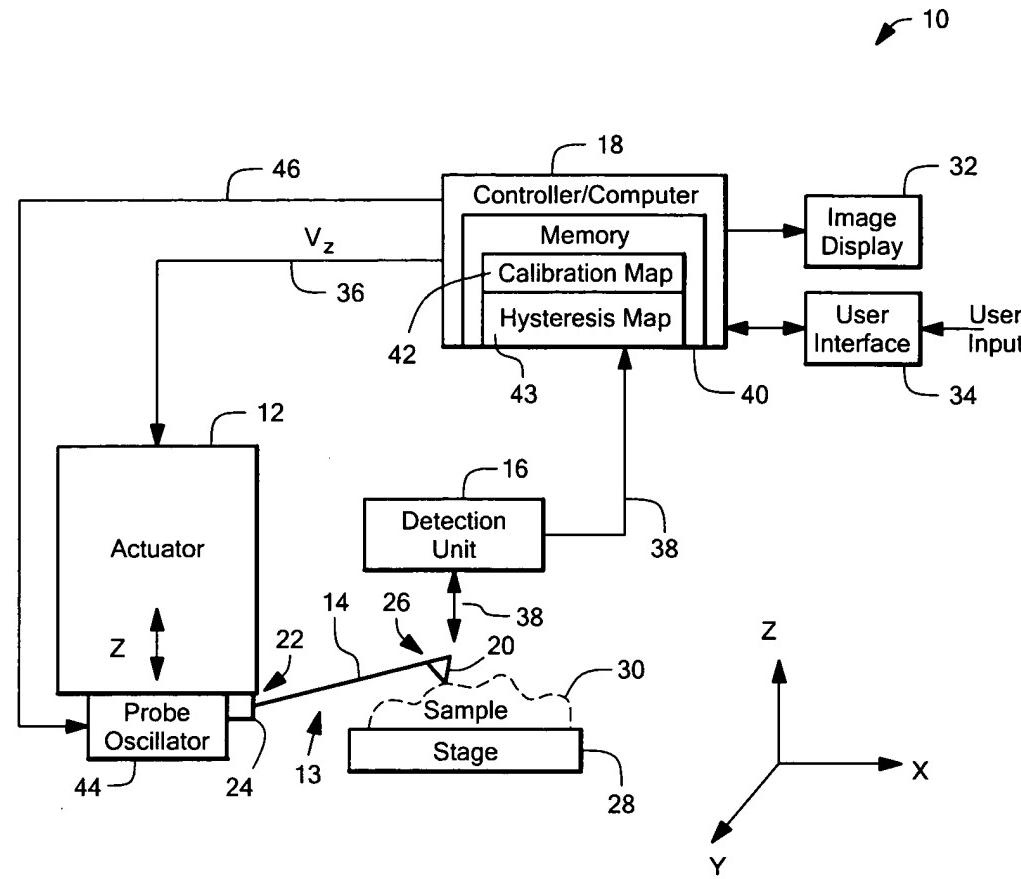


FIG. 1

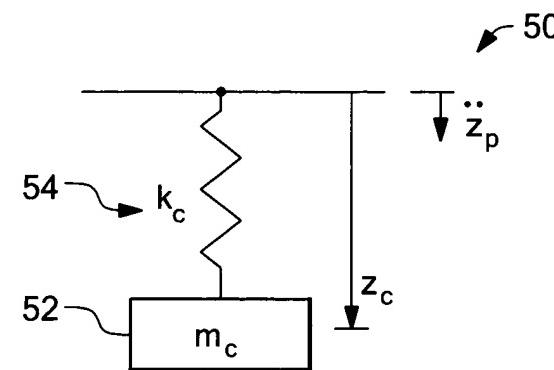


FIG. 2

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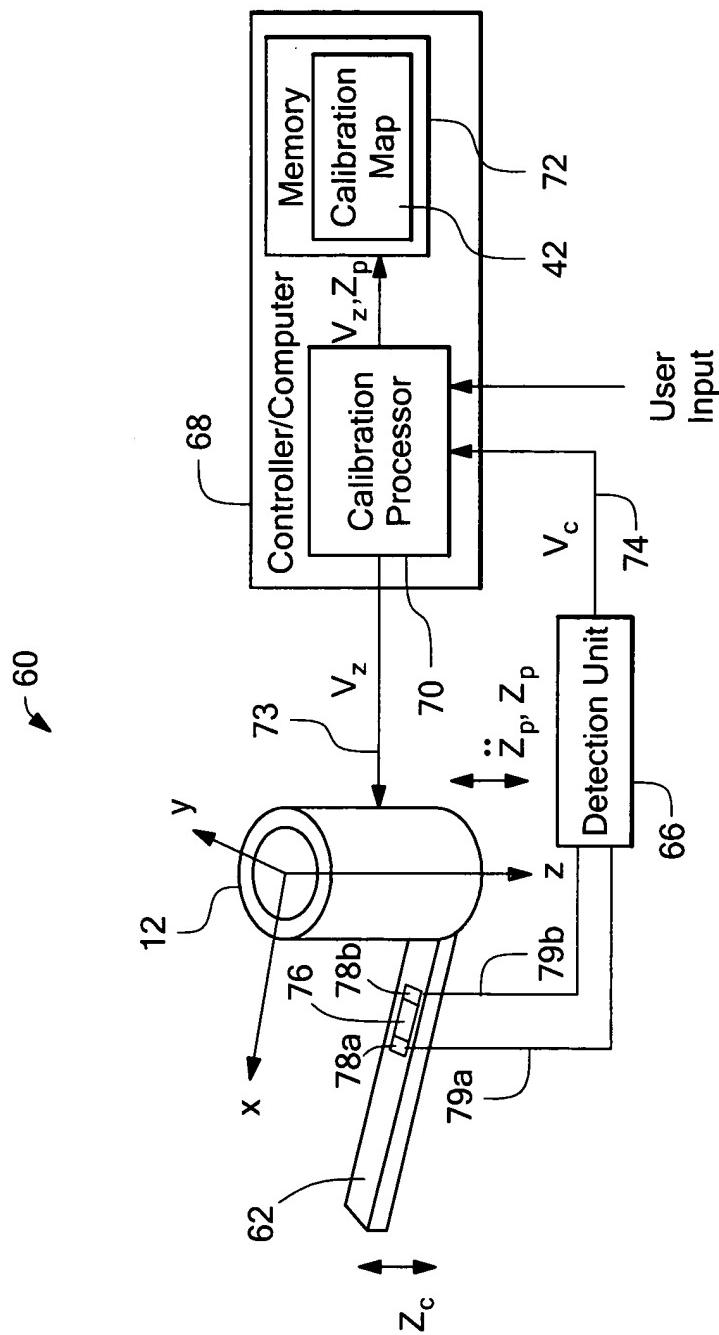


FIG. 3

HEIGHT CALIBRATION OF SCANNING PROBE MICROSCOPE ACTUATORS

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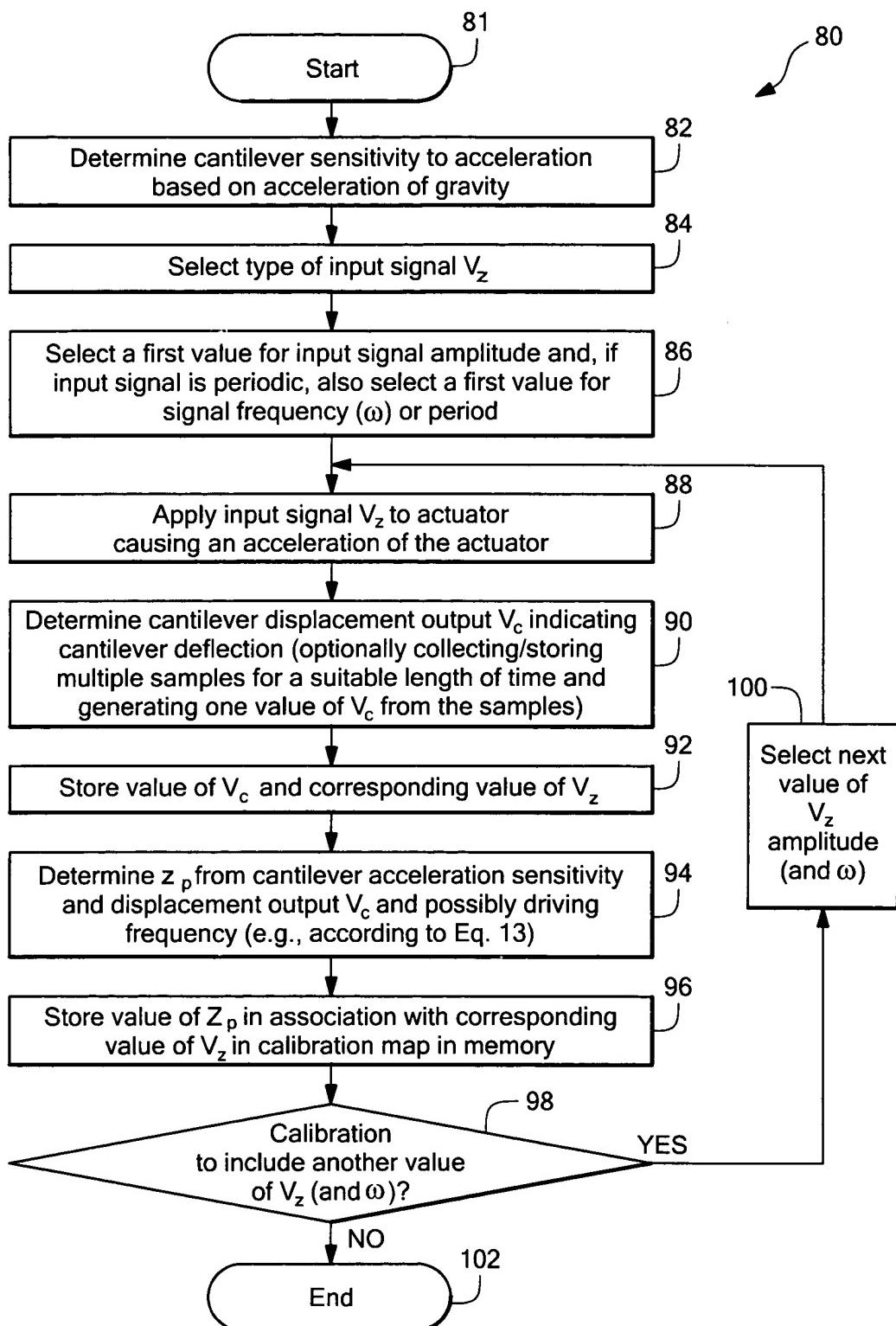


FIG. 4

HEIGHT CALIBRATION OF SCANNING PROBE MICROSCOPE ACTUATORS

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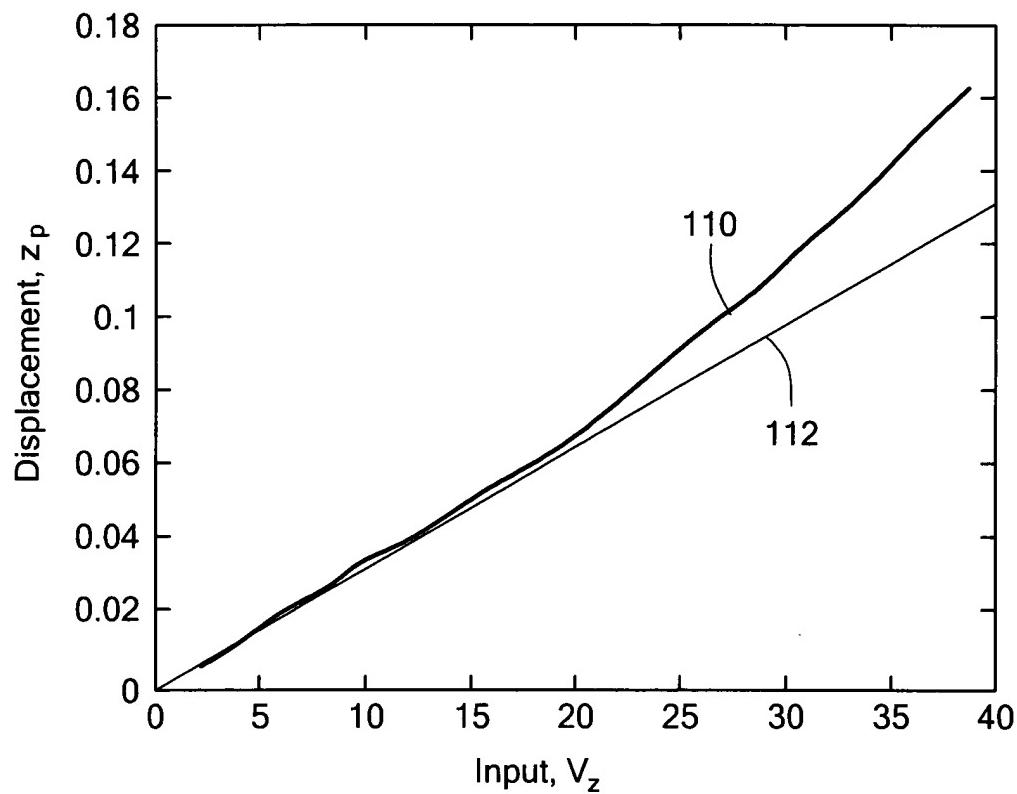


FIG. 5

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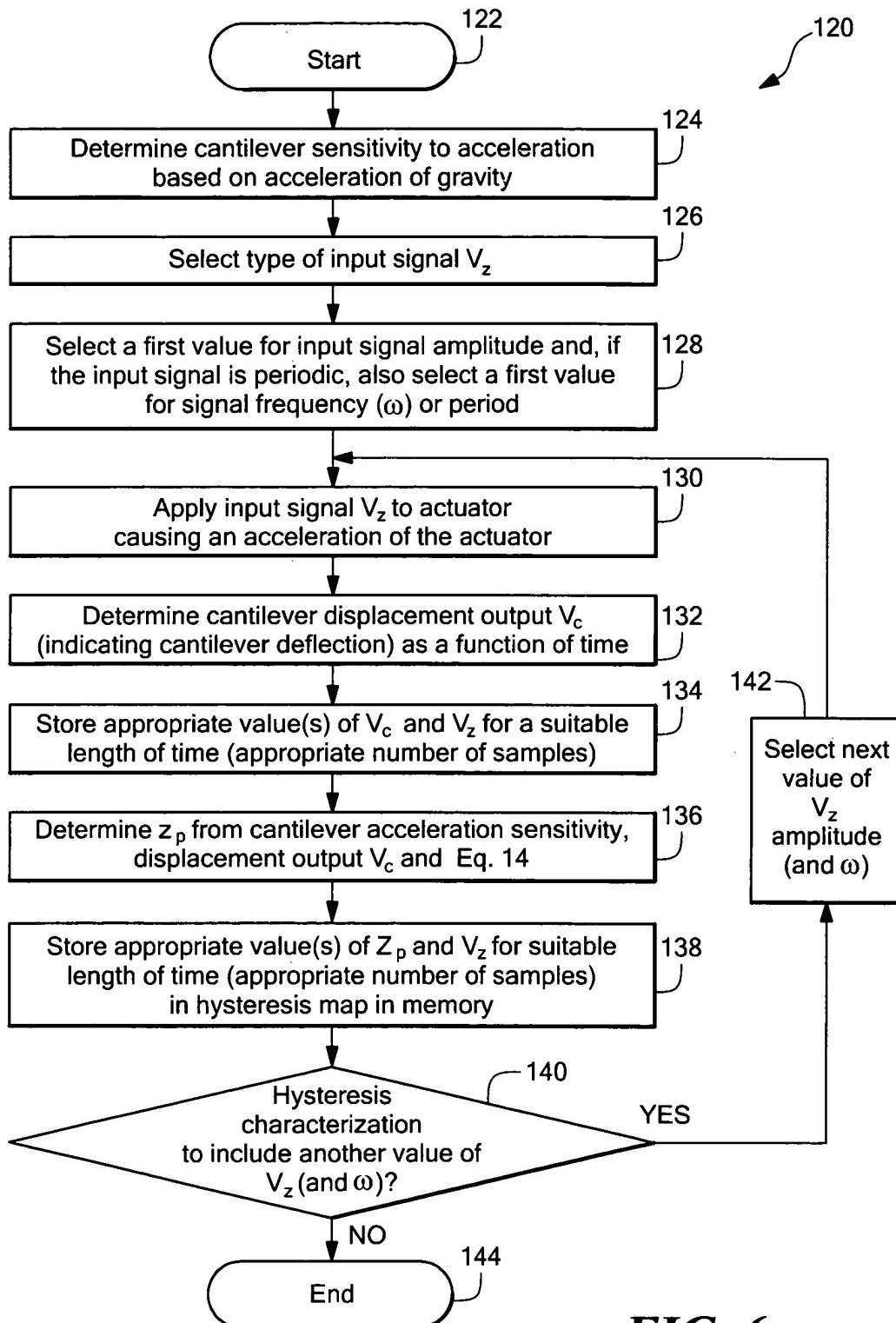


FIG. 6

HEIGHT CALIBRATION OF SCANNING PROBE MICROSCOPE ACTUATORS

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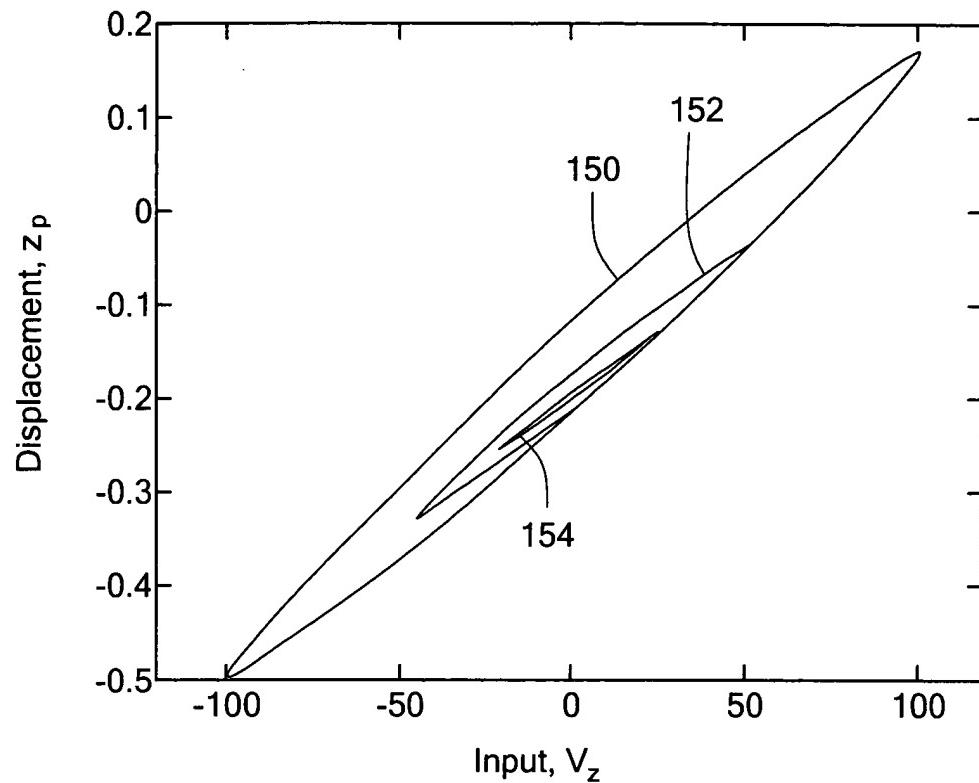


FIG. 7

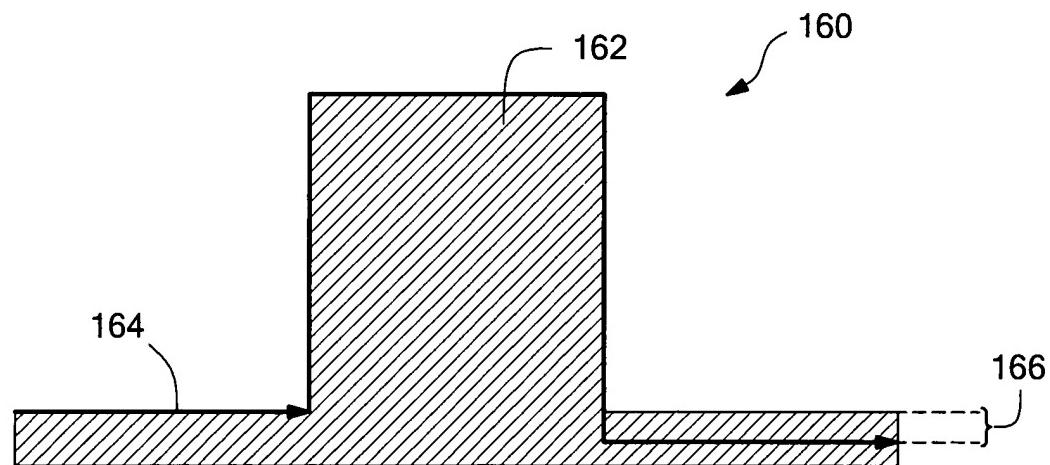


FIG. 8